



Institut des  
Nanotechnologies  
de Lyon UMR 5270

# Fabrication of twisted bilayer photonic crystals (*moirés*) by Nano Printing Stepper (NPS) process

Lydie Ferrier, Maxime Gayrard, Ha My Dang, Céline Chevalier  
Hai-Son Nguyen, Xavier Letartre

*J-NIL 11/05/2023*



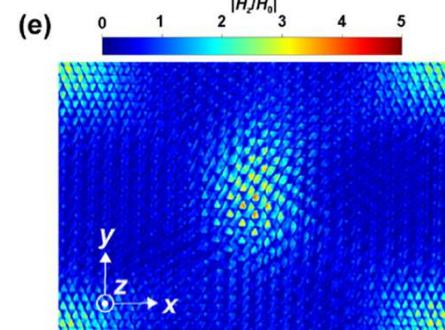
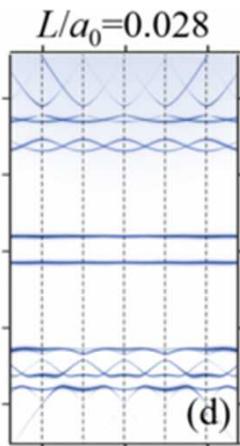
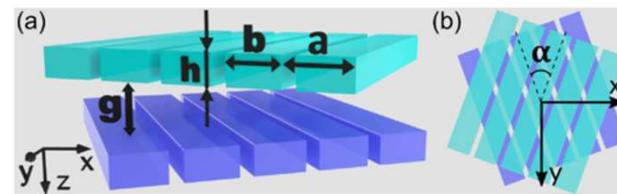
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<http://inl.cnrs.fr>

# Context (1) : twisted bilayer photonic crystals

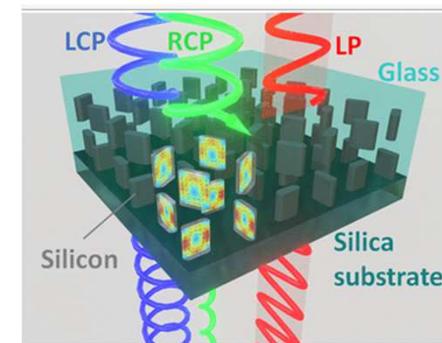
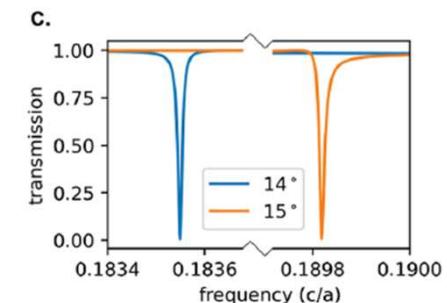
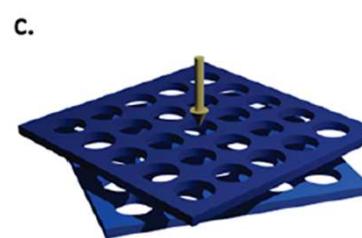
## Novel photonic concepts

- ▶ Non trivial topology
- ▶ Extreme slow light
- ▶ Localization/Delocalization of light



## Novel photonic devices

- ▶ Filters
- ▶ Chiral devices
- ▶ Polarization control of light



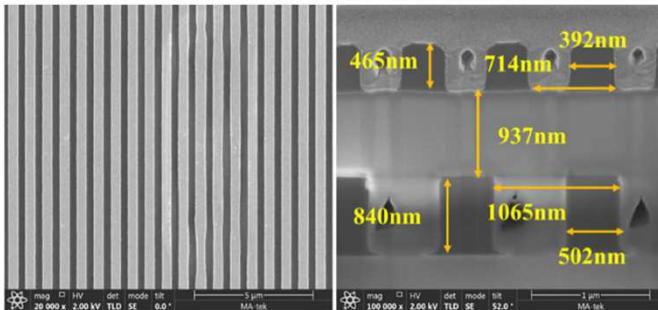
- Yi, C. H., et al (2022). *Light: Science & Applications*, 11(1), 289.  
 Tang, H et al. (2021). *Light: Science & Applications*, 10(1), 157.  
 Nguyen, D. X., et al. (2022). *Physical Review Research*, 4(3), L032031.  
 Wang, P., et al. (2020). *Nature*, 577(7788), 42-46.

- Lou, B., et al (2022). *ACS Photonics*, 9(3), 800-805.  
 Salakhova, N. Set al. (2023) *Physical Review B*, 107(15), 155402.  
 Lou, B., et al. (2021). *126(13)*, 136101.  
 Qin, H., et al. (2023).. *Light: Science & Applications*, 12(1), 66.

## Context (2) : fabrication process

### *"Standard" fabrication process*

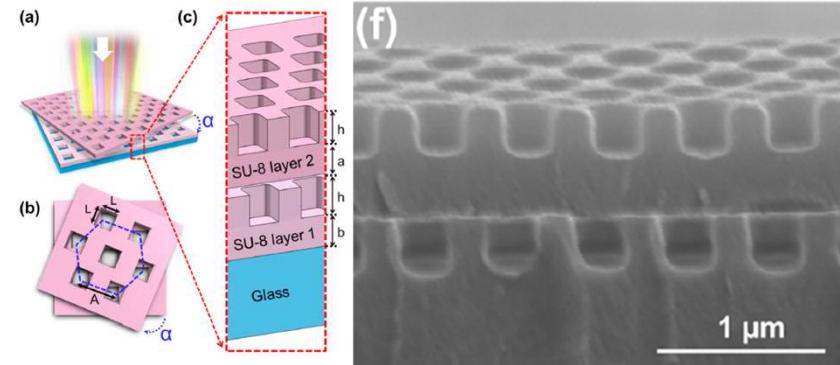
- ▶ 1<sup>st</sup> s-beam lithography, planarization, 2<sup>nd</sup> e-beam lithography (+ alignement)



Zhang, J., et al. (2020). Photonics Research, 8(3), 426-429  
and many other papers !

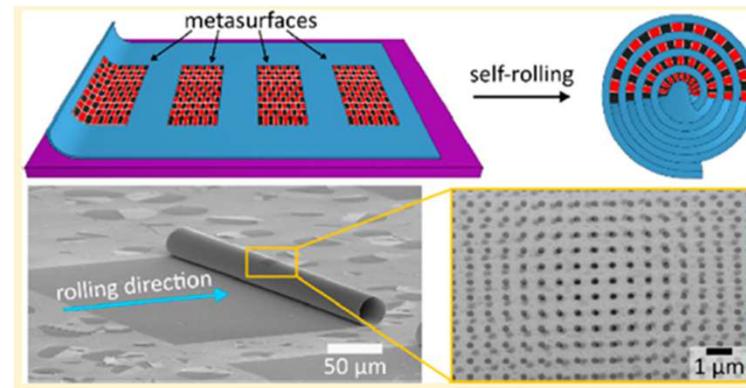
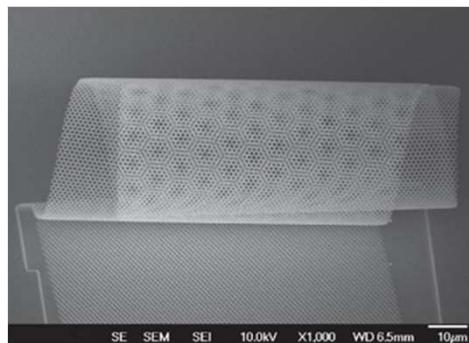
### *Nanoimprint*

- ▶ Reversal NIL process



Chen, M. et al. (2023). Nanophotonics.  
Bergmair, et al. (2011). Nanotechnology, 22(32), 325301.

### *Self-rolled multilayer*

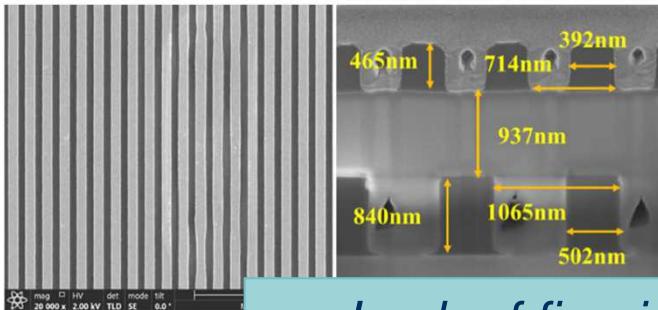


Bermúdez-Ureña, E., et al (2019) ACS Photonics, 6(9), 2198-2204.  
Danescu, A. (2018). Nanotechnology, 29(28), 285301.

## Context (2) : fabrication process

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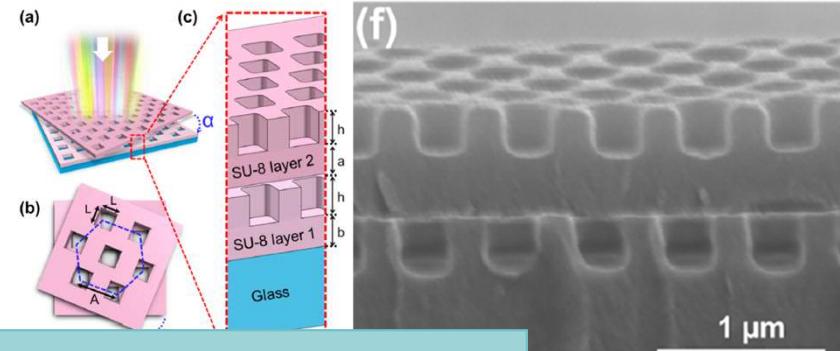
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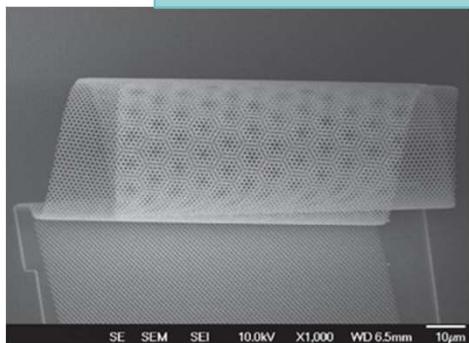
### *Nanoimprint*

- ▶ Reversal NIL process

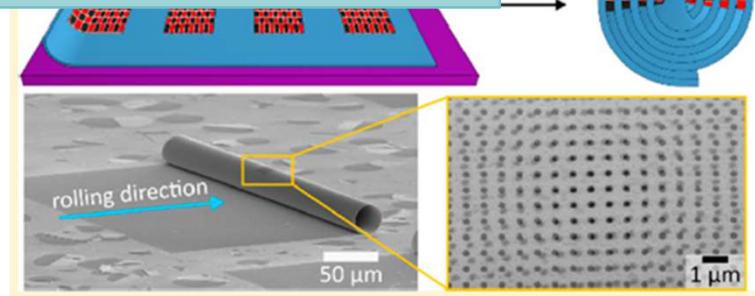


; 22(32), 325301.

### *Self-rolling*



*Lack of fine in-plane and angle tuning  
between layers*  
*High distance between layers (> few  
100nm)*

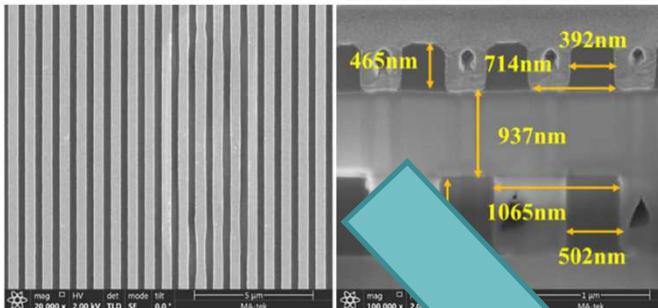


Bermúdez-Ureña, E., et al (2019) ACS Photonics, 6(9), 2198-2204.  
Danescu, A. (2018). Nanotechnology, 29(28), 285301.

# Objectives : twisted bilayer photonic crystals

## *"Standard" fabrication process*

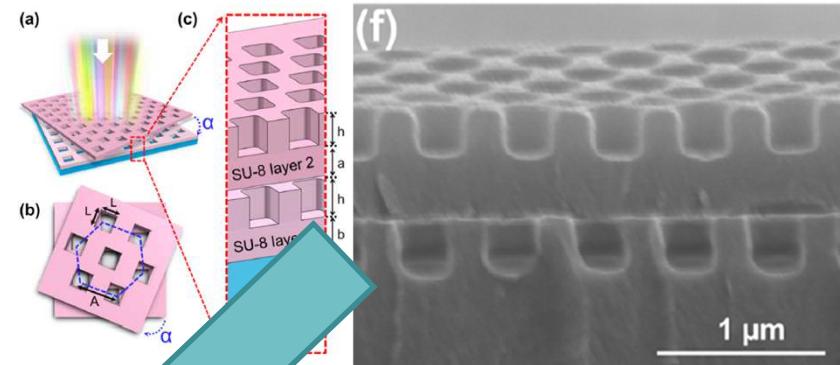
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Zhang, J., et al. (2020). *Photonics Research*, 8(1), 1–10. doi:10.1119/1.1542023  
and many other papers !

## *Nanoimprint*

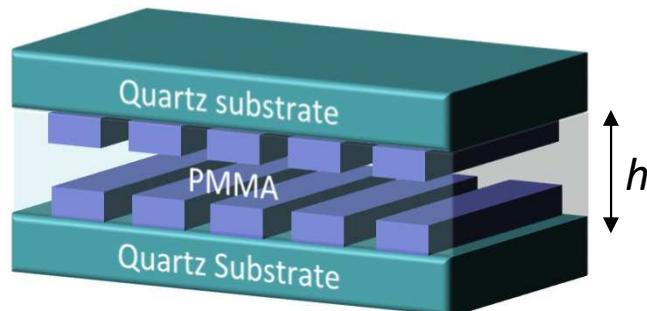
- ▶ Reversal NIL process



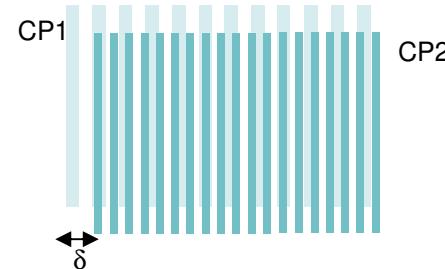
Chen, Y., et al. (2023). *Nanophotonics*. Berlin, Germany: De Gruyter. doi:10.15488/1023.1111  
Bergman, A., et al. (2011). *Nanotechnology*, 22(32), 325301.

## *Standard process + Nano Printing Stepper*

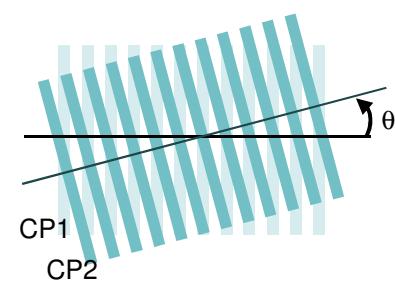
- ▶ Fine control of the distance  $h$  between both grating layers



- ▶ Accurate in-plane tuning



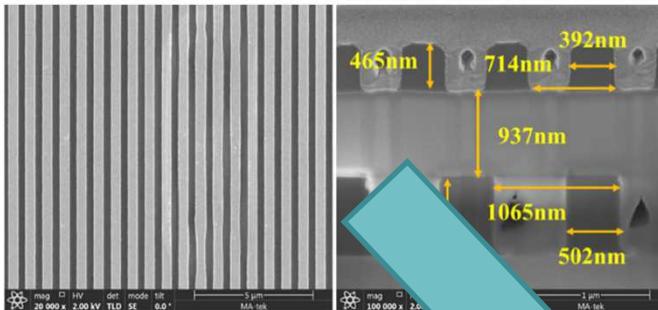
- ▶ Accurate angle tuning



# Objectives : twisted bilayer photonic crystals

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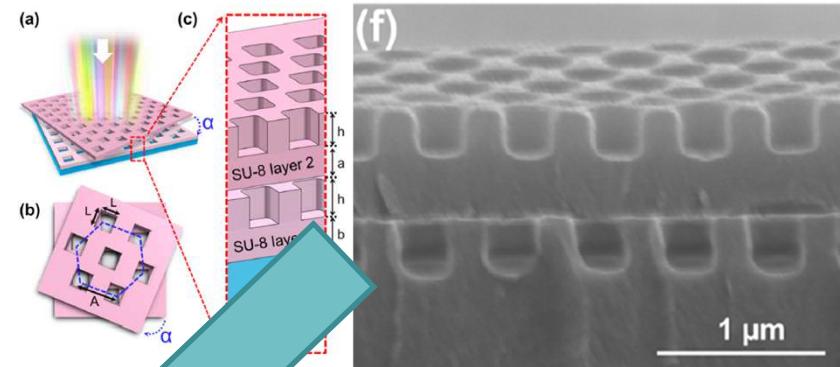
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Zhang, J., et al. (2020). *Photonics Research*, 8(1), 1–10. doi:10.1364/PRJ.360001  
and many other papers !

## *Nanoimprint*

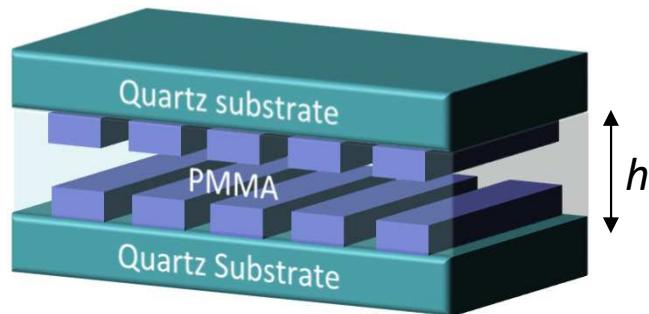
- ▶ Reversal NIL process



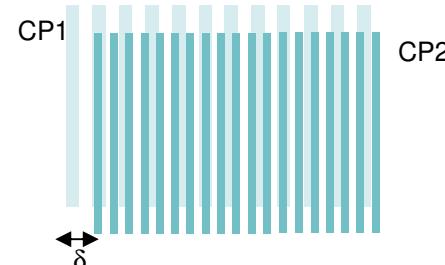
Chen, Y., et al. (2023). *Nanophotonics*. Berlin, Germany: De Gruyter. doi:10.15488/12023.  
Bergman, A., et al. (2011). *Nanotechnology*, 22(32), 325301. doi:10.1088/0957-4484/22/32/325301

## *Standard process + Nano Printing Stepper*

- ▶ Fine control of the distance  $h$  between both grating layers

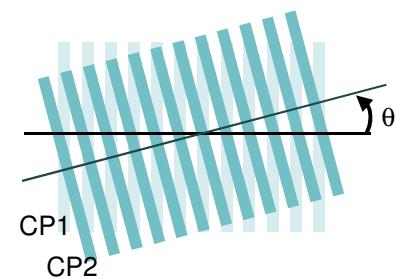


- ▶ Accurate in-plane tuning



- ▶ + wafer bonding (PMMA)

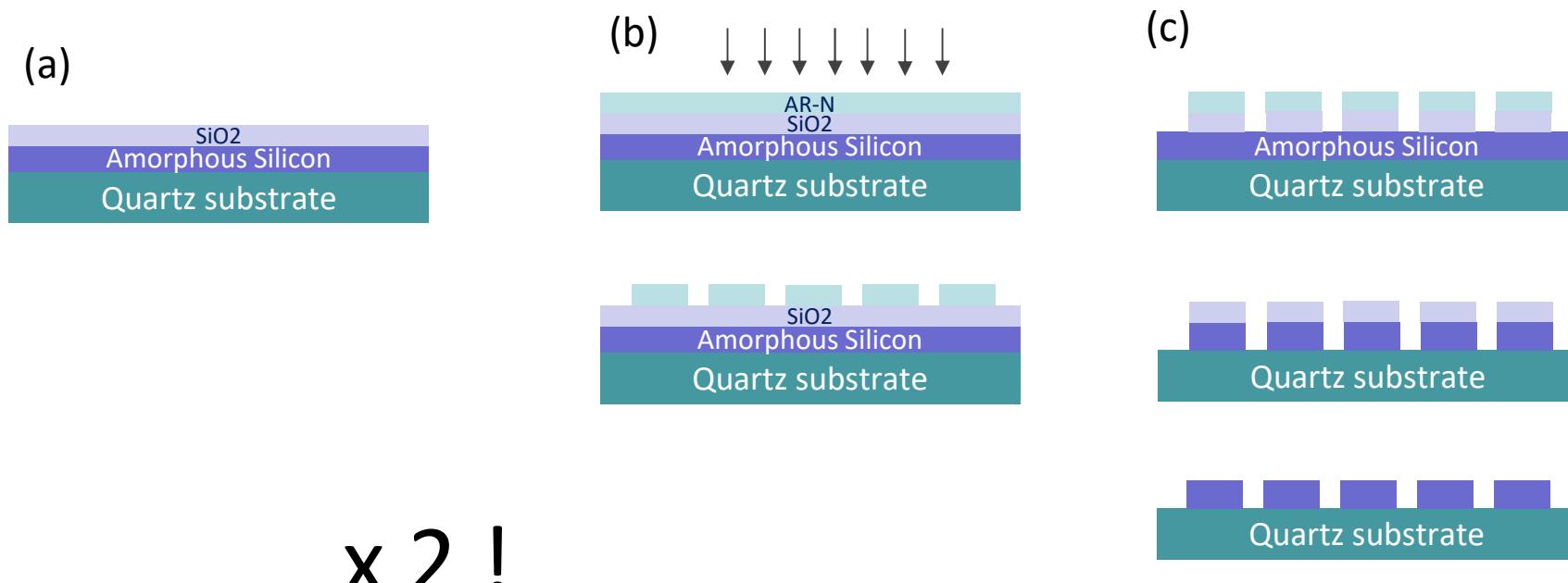
- ▶ Accurate angle tuning



# Technological steps (1)

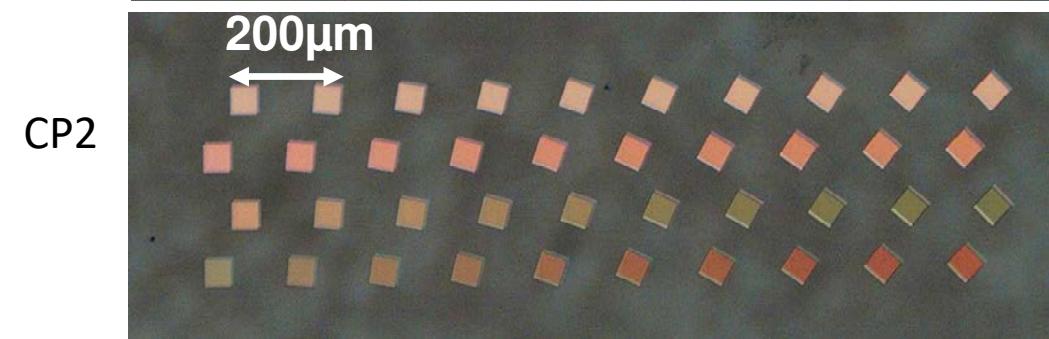
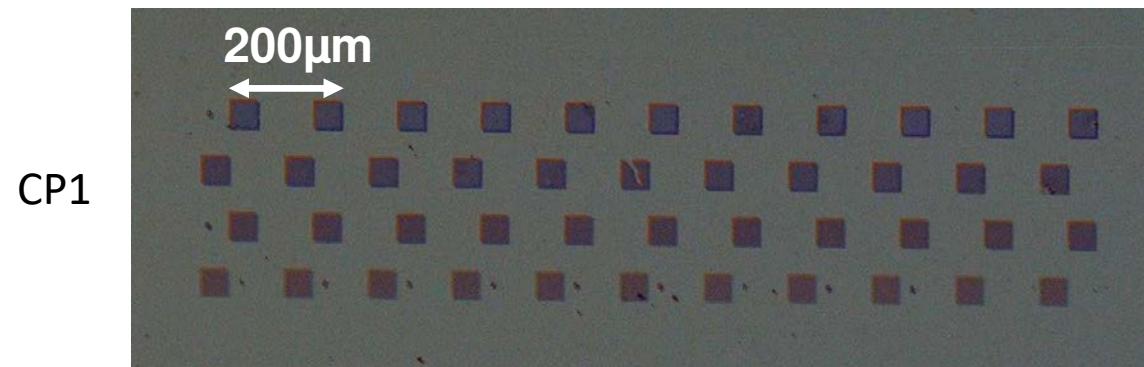
► 1) Fabrication of each grating layer (two samples):

- (a) Amorphous silicon and SiO<sub>2</sub> deposition (PECVD)
- (b) E-beam lithography of alignment marks + PhC
- (c) Dry etching (ICP)



# Technological steps (1)

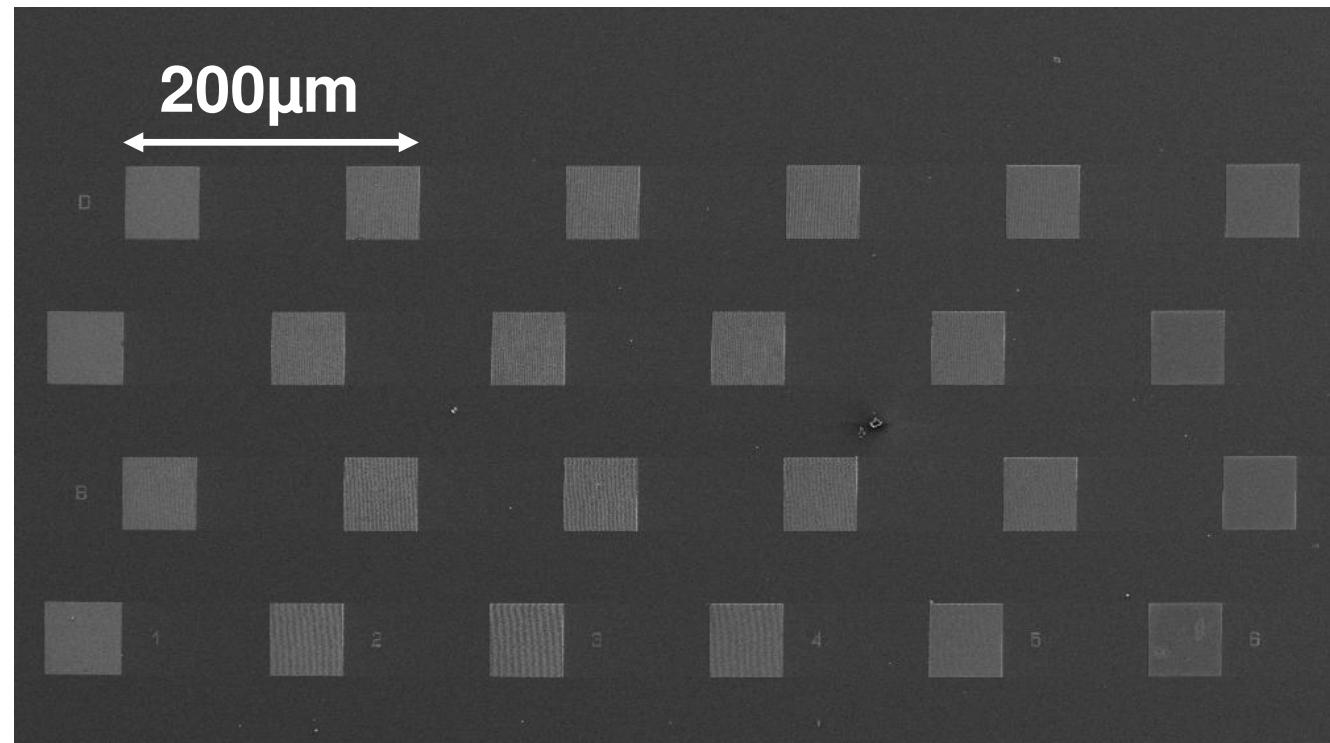
- ▶ 1) Fabrication of each grating layer (two samples):
  - ▶  $\mu$ scope images



$0^\circ$  ——————  $45^\circ$

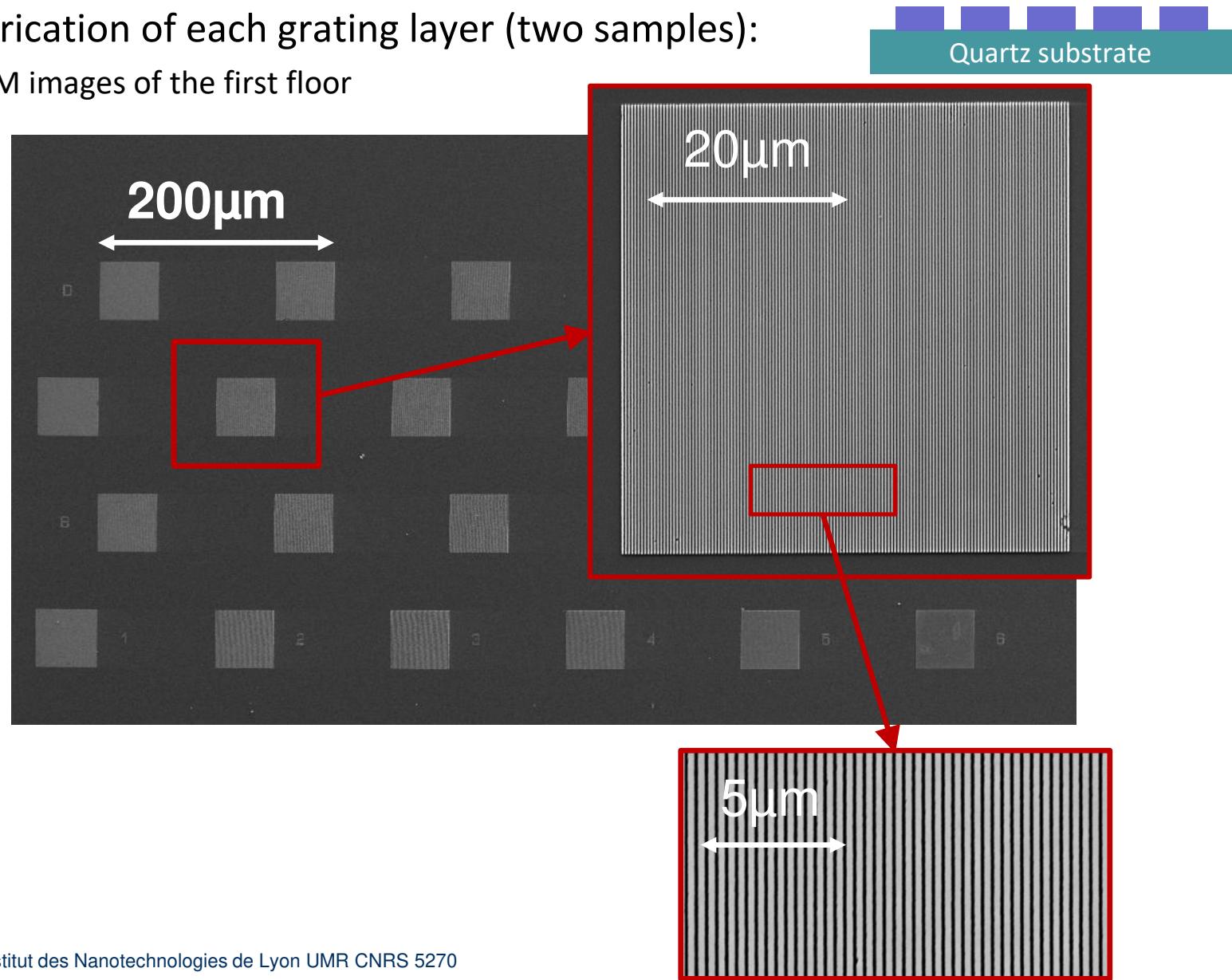
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- ▶ 1) Fabrication of each grating layer (two samples):
  - ▶ SEM images of the first floor



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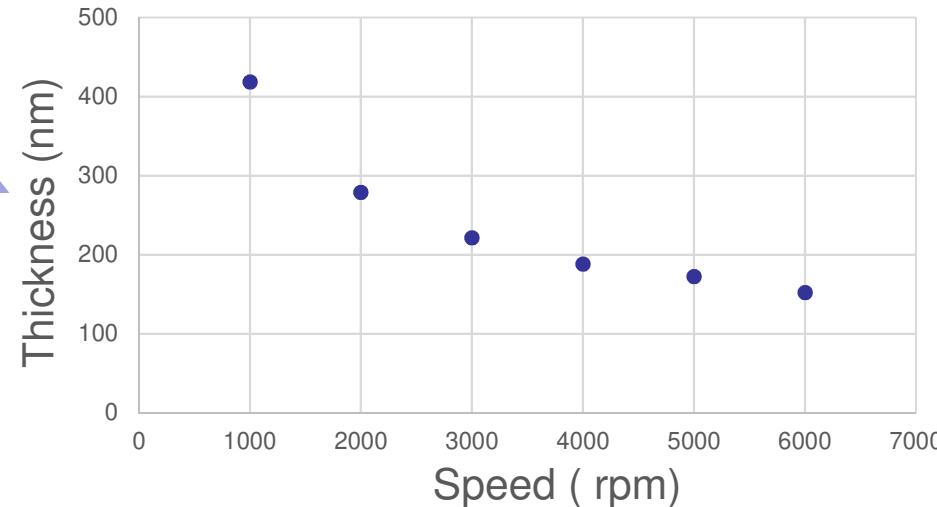
- ▶ 1) Fabrication of each grating layer (two samples):
  - ▶ SEM images of the first floor



# Technological steps (2)

- ▶ 2) Bonding by using Nano Patterning Stepper :
  - ▶ (a) Spin coating of PMMA

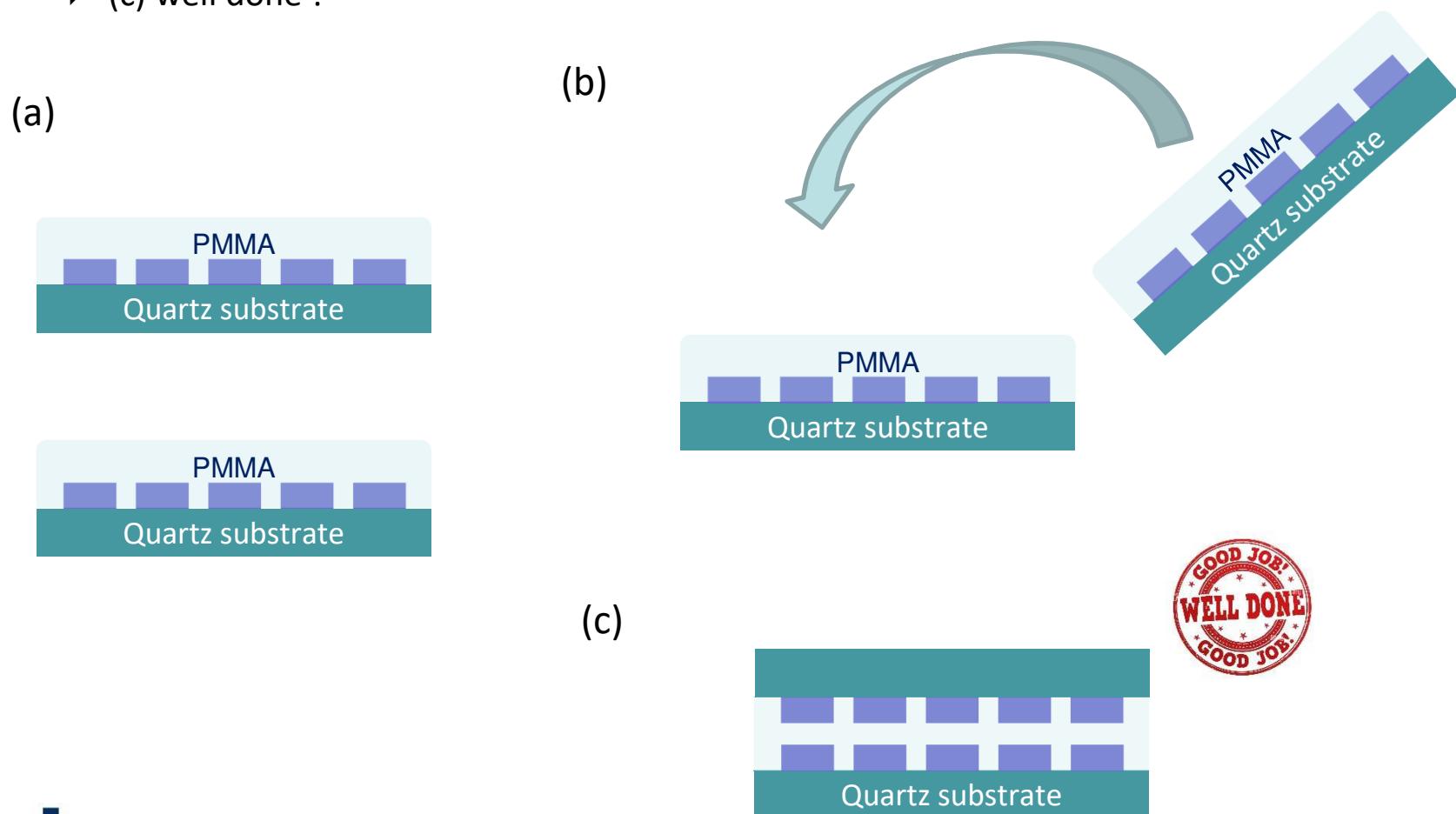
(a)



# Technological steps (2)

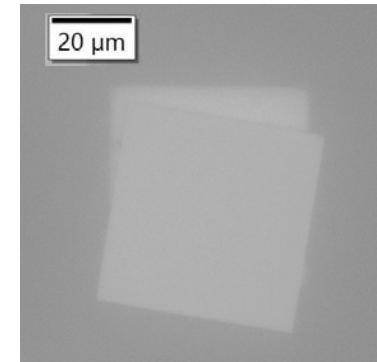
## ► 2) Bonding by using Nano Patterning Stepper :

- (a) Spin coating of PMMA
- (b) Alignment & bonding (+ Temperature, Time and Pressure optimization)
- (c) well done !



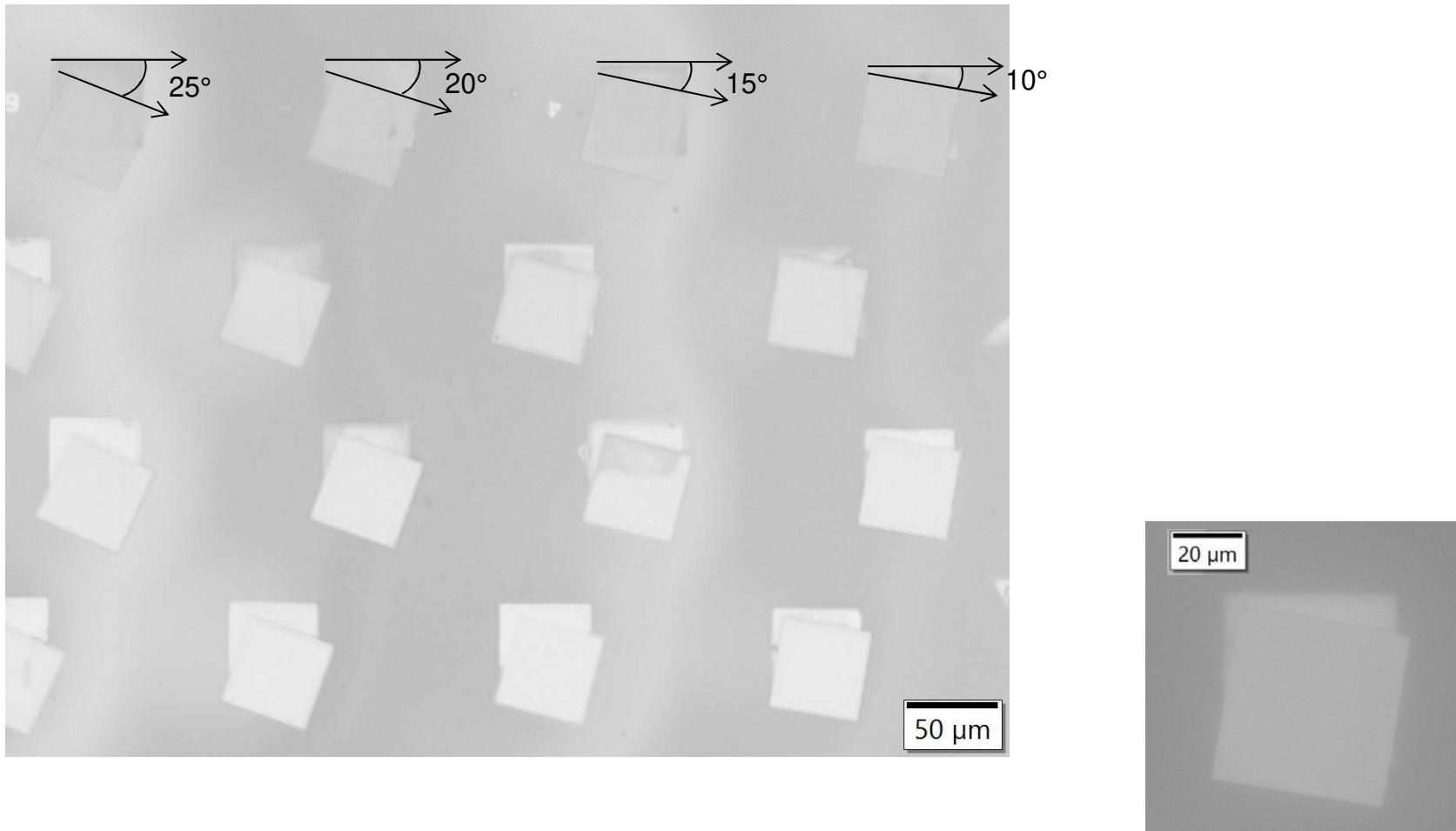
# First results

- ▶ Bonding ok
- ▶ Slight misalignment (but human mistake !) of about  $1^\circ$



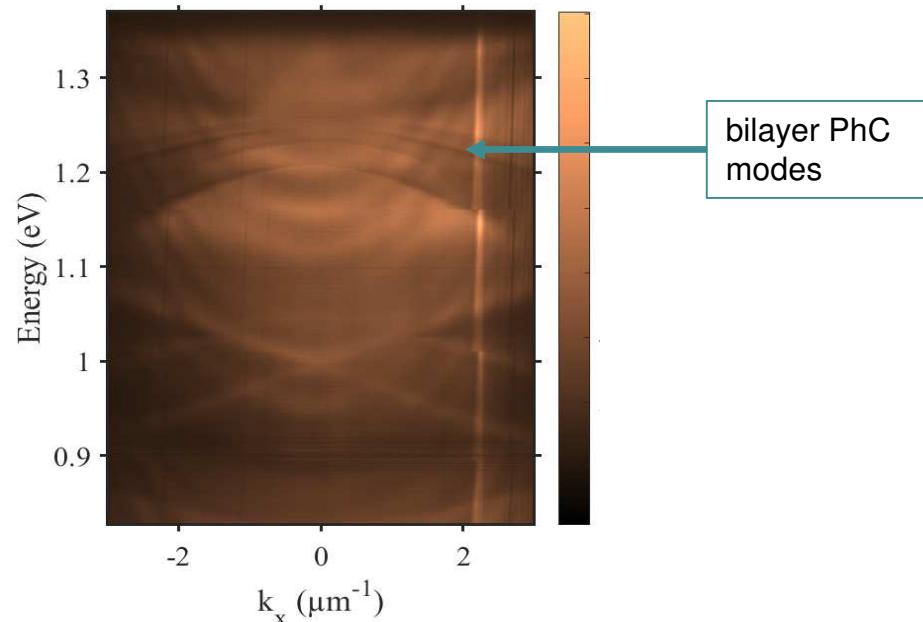
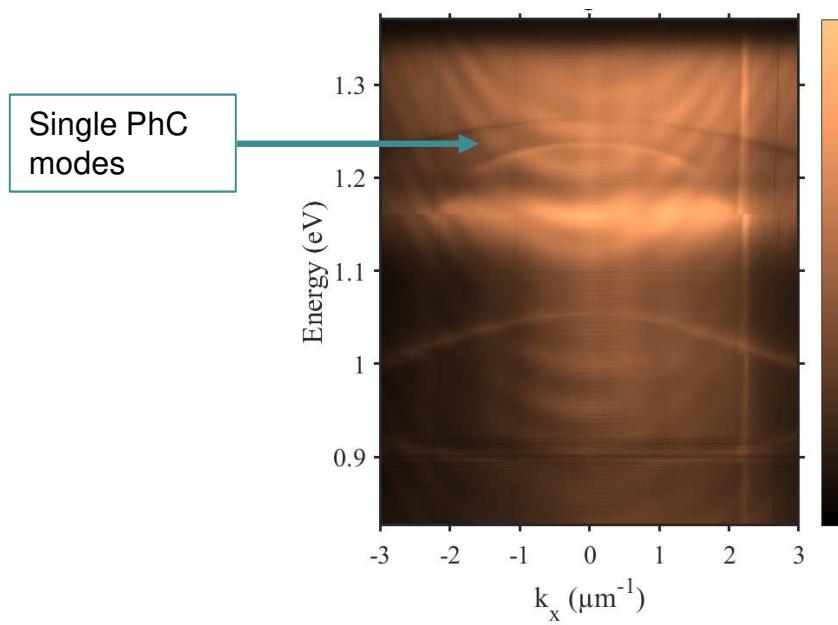
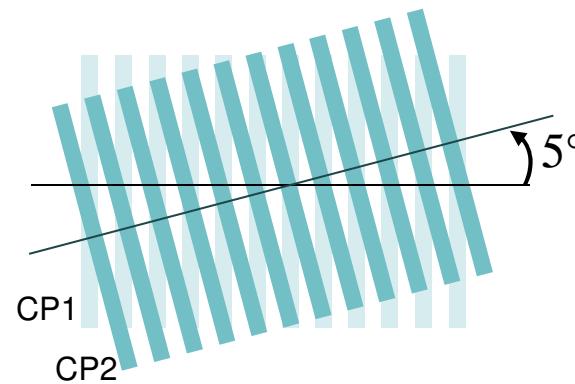
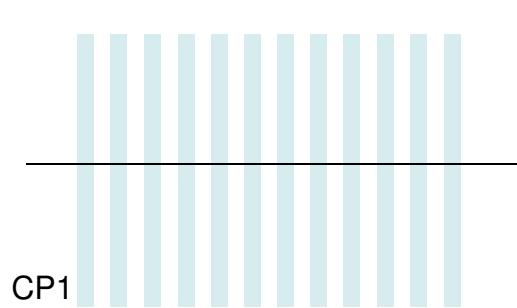
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# First optical measurements

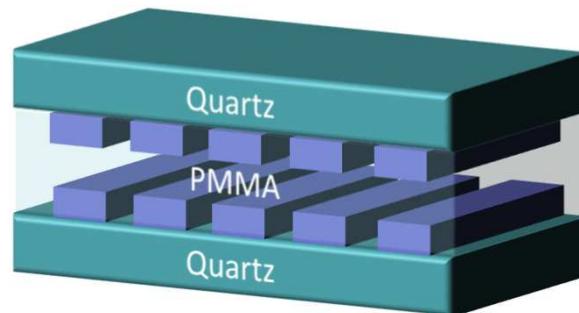
- ▶ IR Fourier space imaging of single and bilayer photonic crystals



# Conclusion and Perspectives

## ► Fabrication of bilayer photonic crystals :

- ✓ E-beam lithography of photonic crystals and alignment marks: patterning on a-Si layers on transparent substrates
- ✓ Bonding and alignment thanks to NPS process
- ✓ Thermoplastic polymer (PMMA) as bonding layer



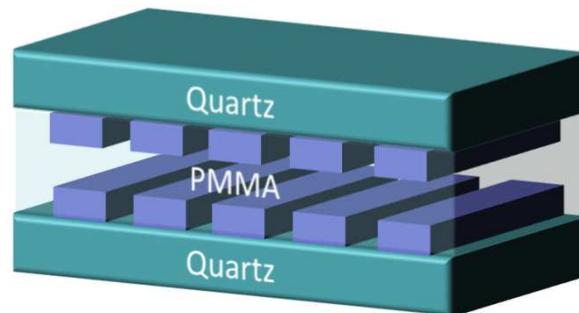
## ► Versatile process:

- ✓ Active structures (eg. by using III-V or QD in PMMA or perovskite)
- ✓ Many degrees of freedom :
  - ✓ Materials
  - ✓ Dimensions
  - ✓ Fine tuning of both layers

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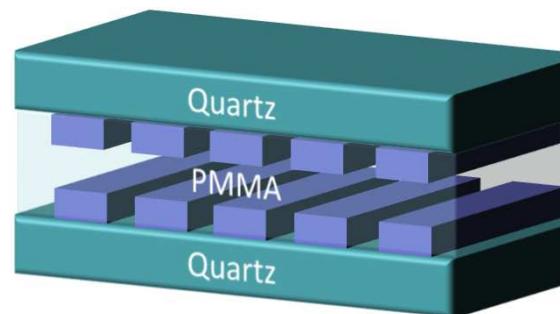
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THANK YOU FOR YOUR  
ATTENTION



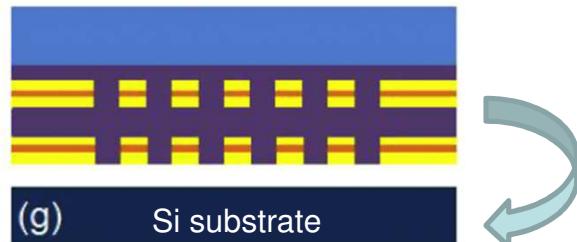
# Perspectives



} Passive structure

## ► Perspectives :

- Active devices :
  - perovskite, doped PMMA...
  - PCM
- Multiple layers ?
  - Fabrication of the Phc on a sacrificial layer



Nanotechnology 22 (2011) 325301 (6pp)

doi:10.1088/0957-4484/22/32/325301

## Single and multilayer metamaterials fabricated by nanoimprint lithography

